HGCal module test at IHEP

Zhipeng Cui, Pei-Zhu Lai On behalf of the Chinese HGCal group

CLHCP 2024 November 15, 2024





中國科學院為能物記研究所 Institute of High Energy Physics Chinese Academy of Sciences



Outline

□ Introduction

Testing Procedure

Quality Assurance & Control

Alignment

Electronic

DIV Responce

Database

DSummary and Outlook

Introduction

Significance of Testing

•One of crucial procedures in HGCAL assembly.

I. Identified the final quality of HGCAL modules.

2. Make sure no damage caused after each assembly process.

•Quality assurance and control criteria

I. Alignment

. . .

2. Number of electronic readout and noise level

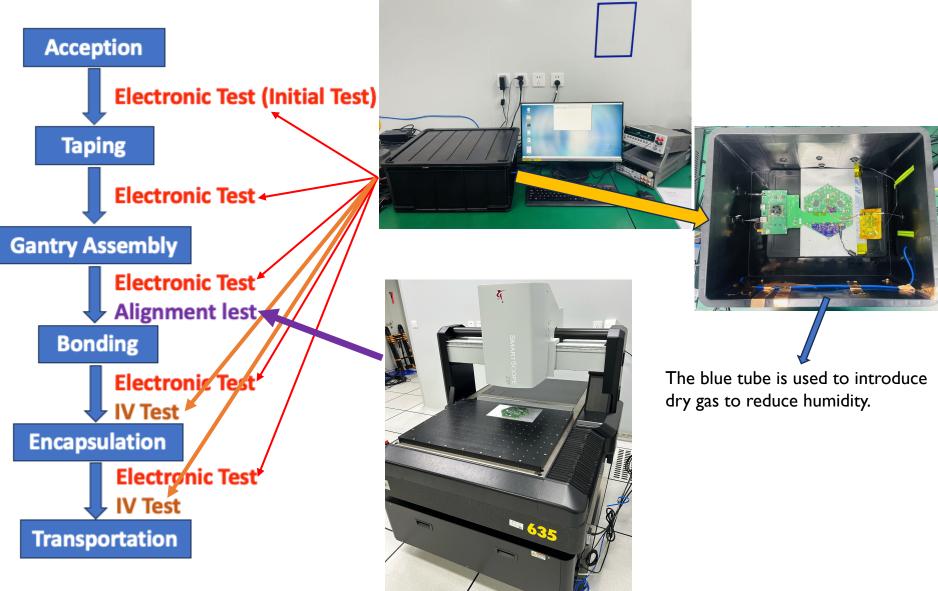
3. IV response (Current v.s. Voltage)

•Also important features but not in the final grading

I. Flatness of baseplate

2. Bonding wire tightness

Testing Procedure



Module production procedure

Optical Gaging Product (OGP)

Alignment

Summarized Accuracy Plot

- Sensor wrt Baseplate
 Baseplate
- PCB wrt Baseplate

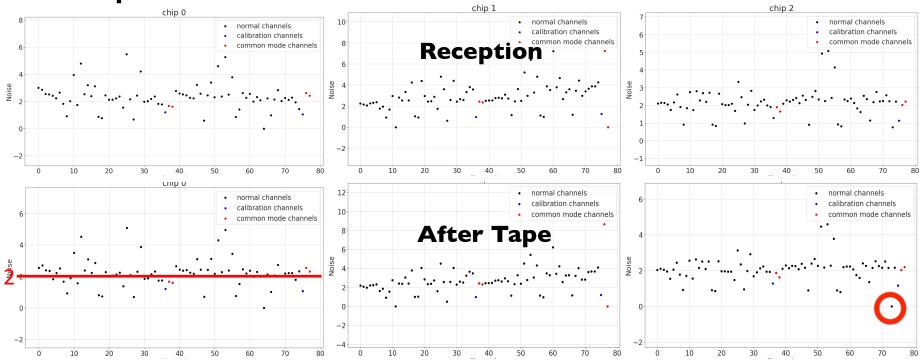
< 150 µm & < 0.1 degree 0.04 0.06 0.06 300 0.08 -0.08 PCB 200 $\Delta y ~[\mu m]$ (84, 486)100 μm HGCROC 100 Silicon Kapton 0 Baseplate (e.g. Cu/W) -100-200 - 100100 200 0 $\Delta x [\mu m]$ Basically like making a "sandwich".

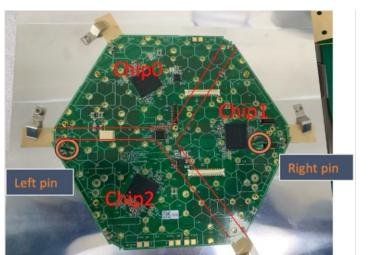
- □ All alignments met the grade A criteria except one manual accident.
- □ Gantry guys did a good job!

Grade A: misplacement of X and Y

Electronic Test

For example:

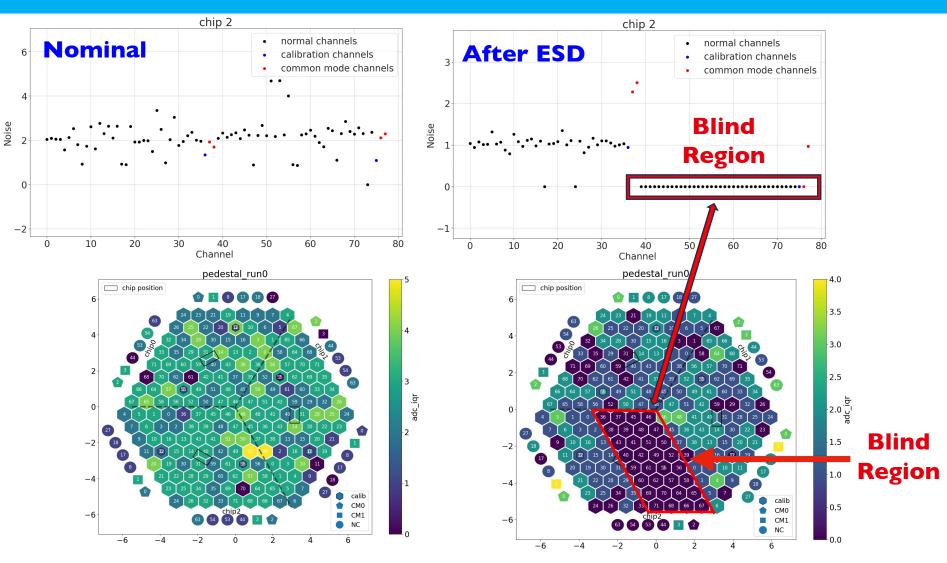




I.Check whether introduce additional dead channels after each process.

2.Exam whether the noise level is reasonable, (2 ADCs).

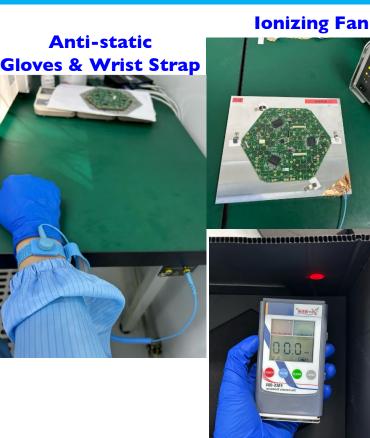
Electrostatic Discharge (ESD)



IHEP was the first lab aware of ESD, which was later confirmed by CERN.
The corresponding ESD protection measures have been applied.

ESD Protection Measures

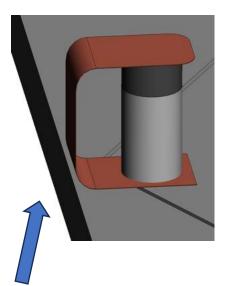




Anti-static box

Initial ESD protections measures:

- Both People and equipment are grounded
- Anti-electrostatic gloves for operation
- Ionizing Fan
- Anti-electrostatic box for transportation



Additional protection applied:

Ground HV capacitor using a conductor connected to fixture used for transfer tape tasks

Electronic Test Summary

* 7 Pre-Production

Module IDs	PCB ID	# of Dead Channels	Grade A (# < 10)
ML_F3WX_IH_00014	02	0	Α
ML_F3WX_IH_00015	09	0	Α
ML_F3WX_IH_00016	10	0	Α
ML_F3WX_IH_00017	03	0	Α
ML_F3WX_IH_00018	01	0	Α
ML_F3WX_IH_00019	04	0	Α
ML_F3WX_IH_00020	101	0	Α
# of A			7

• The quality of this batch of PCB boards is exceptionally high.

Electronic Test Summary

* 10 Pre-Series

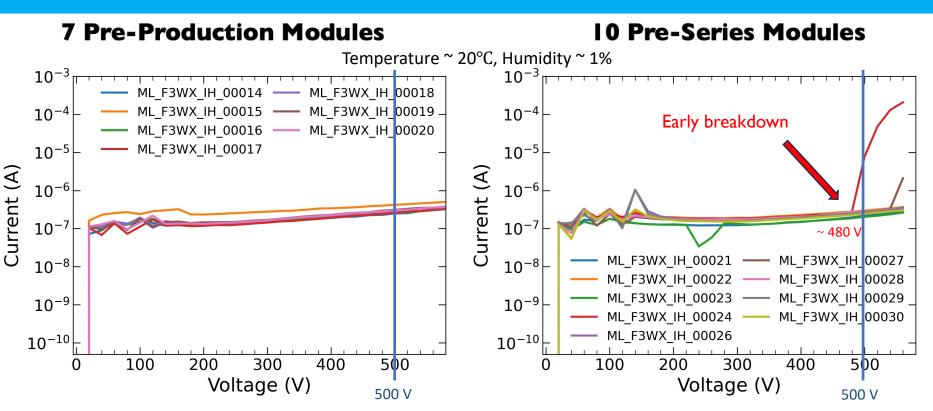
Module IDs	PCB ID	# of Dead Channels	Grade A (# < 10)	
ML_F3WX_IH_00021	84	6	Α	
ML_F3WX_IH_00022	60	3	Α	
ML_F3WX_IH_00023	53	14	A*	
ML_F3WX_IH_00024	45	4	Α	
ML_F3WX_IH_00025	54	8	Α	
ML_F3WX_IH_00026	55	3	Α	
ML_F3WX_IH_00027	56	2	Α	
ML_F3WX_IH_00028	57	8	Α	
ML_F3WX_IH_00029	58	13	A*	
ML_F3WX_IH_00030	59	8	Α	
# of A			8	

•Did not introduce any additional dead channel from our assembly.

(All dead channels are from initial PCB itself.)

•8 PCBs were "A" when we received them; the other 2 were A*.

IV Test Summary



•Grade A: Breakdown voltage > 500 V for now and I(850 V) / I(600 V) < 2.5 will be added in future.

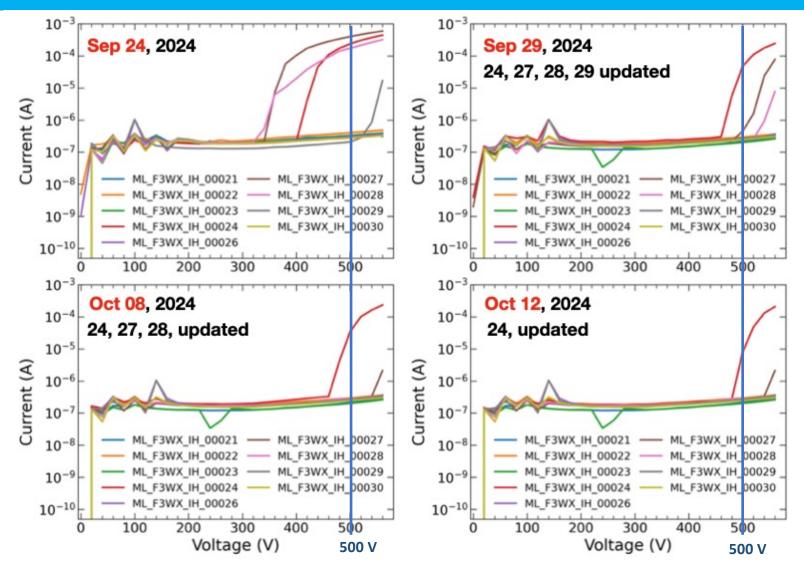
•16 modules are graded as A.

•Potential reasons for early breakdown:

• Humidity between the layers need to be dissipated.

• • •

IV Test as Time



Break down voltages of module number 24, 27, 28, 29 are getting greater as time pass by.
Humidity, glue spreading across the guard ring, and insufficient drying may be the causes.

Database

System --developed by CMU

Module Setup Live Module - Hexaboard Hexaboard Density: Low Module - Mexaboard Hexaboard Density: Low Module - Mexaboard Hexaboard Shape: Sensor Thickness: 120 micron 200 micron Baseplate Type: PCB - Carbon Fiber - Copper-Tungsten Preseries Module Module Serial Number: 200-ML-F2CX-CM-9999 Test Stand IP: cmstpcattb Inspector: arcobert Module Status: Frontside Encapsulated Configure Test Stand Only IV Test Debug Mode: Status Bar Debug Mode: Nodule: Nodule: Is Live Module: HV Cable Connected: HV Cable Connected:		1
Hexaboard Density: * Low ~ High Hexaboard Shape: * Full ~ Top ~ Bottom ~ Left ~ Right ~ Five Sensor Thickness: 120 micron ~ 200 micron ~ 300 micron Baseplate Type: PCB ~ Carbon Fiber ~ Copper-Tungsten * Preseries Module Trim Pedestals Bias Voltage: Module Index: Image: Standard Test Procedure Scan QR Code: Clear Module Serial Number: 320-ML-F2CX-CM-9999 Test Stand IP: msspcattb4.lan.local.cmu.edu Inspector: acrobert Module Status: Frontside Encapsulated Configure Test Stand Only IV Test * Debug Mode * Skip Electrical Checks Close GUI Status Bar Debug Mode: Debug Mode: Dark Box Closed: DCDC Powered Tophy Connected: Mexacontroller Powered: DAQ Server: Its Live Module: Bark Box Closed: DCDC Powered		
Hexaboard Density: ● Low O High Hexaboard shape: ● Full ● Top ● Bottom ● Left ● Right ● Five Sensor Thickness: 120 micron ● 200 micron ● 300 micron Baseplate Type: ● CB ● Carbon Fiber ● Copper-Tungsten ☑ Preseries Module Module Index: 1000 Scan QR Code: Clear Module Serial Number: 320-ML-F2CX-CM-9999 Test Stand IP: cmshgaatb4.lan.local.cmu.edu Inspector: acrobert Module Status: Frontside Encapsulated Configure Test Stand Only IV Test I Debug Mode Skip Electrical Checks Close GU Status Bar Debug Mode: Dark Box Closed: I Status Bar Dark Box Closed: DCDC Powered Trophy Connected: Hexacontroller Powered: DAQ Server:		
Hexaboard shape: • Full • Top • Bottom • Left • Right • Five Sensor Thickness: • 120 micron • 200 micron • 300 micron Baseplate Type: • PCB • Carbon Fiber • Copper-Tungsten Preseries Module Module Index: Standard Test Procedure Trim Pedestals Bias Voltage: 300 Pedestal Run Number of tests: Bias Voltage (per run): Other Test Script: Bias Voltage: 300 Ambient IV Curve Dry IV Curve Number of tests: Bios Voltage: Only IV Test Pebug Mode Skip Electrical Checks Close GUI Status Bar Debug Mode: Is Live Module: Dark Box Closed: DCDC Powered Trophy Connected: 	Hexaboard Density: ◎ Low ○ High	
Sensor Thickness: 120 micron 200 micron 300 micron Baseplate Type: PCB Carbon Fiber Copper-Tungsten Image: Preseries Module Module Index: Image: Preseries Module Module Serial Number: 320-ML-F2CX-CM-9999 Test Stand IP: Ciear Module Serial Number: 320-ML-F2CX-CM-9999 Test Stand IP: Cimshqcaltbd.lan.local.cmu.edu Inspector: acrobert Module Status: Frontside Encapsulated Configure Test Stand Only IV Test Status Bar Debug Mode:	Hexaboard shape: ◎ Full ○ Top ○ Bottom ○ Left ○ Right ○ Five	Tests to run:
Baseplate Type: PCB Carbon Fiber Copper-Tungsten Image: Preseries Module Module Index: Image: Preseries Module Module Index: Image: Preseries Module Module Serial Number: 320-ML-F2CX-CM-9999 Test Stand IP: Image: Preseries Module Module Status: Frontside Encapsulated Image: Preseries Stand Only IV Test Module Status: Frontside Encapsulated Image: Preseries Stand Only IV Test Image: Preseries Stand Image: Preseries Pres		Standard Test Procedure
[™] Preseries Module [™] Preseries Mod		Trim Pedestals Bias Voltage: 300
	Baseplate Type: ○ PCB	□ Pedestal Run_Number of tests:
Module Index: Image: Stand QR Code: Scan QR Code: Clear Module Serial Number: 320-ML-F2CX-CM-9999 Test Stand IP: cmshgcaltb4.lan.local.cmu.edu Inspector: acrobert Module Status: Frontside Encapsulated Configure Test Stand Only IV Test Image: Debug Mode Skip Electrical Checks Close GUI Status Bar Debug Mode: Dark Box Closed: Is Live Module: Dark Box Closed: DCDC Powered Trophy Connected: Hexacontroller Powered: DAQ Server:	Preseries Module	
Scan QR Code: Scan QR Code: Module Serial Number: 320-ML-F2CX-CM-9999 Test Stand IP: cmshgcaltb4.lan.local.cmu.edu Inspector: acrobert Module Status: Frontside Encapsulated Configure Test Stand Only IV Test Debug Mode Skip Electrical Checks Close GUI Status Bar Debug Mode: Is Live Module: Dark Box Closed: DCDC Powered Trophy Connected: DCDC Powered: Hexacontroller Powered: DAQ Server: IzC Server: DAQ Server: IzC Server: DAQ Server: IzC Server: DAQ Server: IzC Server: DAQ Server: DAQ Server: IzC Server: DAQ	Module Index: 0000	
Module Serial Number: 320-ML-F2CX-CM-9999 Test Stand IP: cmshgcaltb4.lan.local.cmu.edu Inspector: acrobert Module Status: Frontside Encapsulated Configure Test Stand Only IV Test Debug Mode Skip Electrical Checks Close GUI Status Bar Debug Mode: Dark Box Closed: DCDC Powered Is Live Module: HV Output Powered: DCDC Powered Hexacontroller Powered: DAQ Server: Is Live Module: HV Output Powered: Trophy Connected: Itexacontroller Accessed: IZC Server: IZC Server:		🗆 Other Test Script: 🔤 🚽 Bias Voltage: 300
Test Stand IP: omshgcattb4.lan.local.cmu.edu Imspector: acrobert	Scan QR Code:	□ Ambient IV Curve
Test Stand IP: cmshgcaltb4.lan.local.cmu.edu Imspector: acrobert	Module Serial Number: 320-ML-F2CX-CM-9999	□ Dry IV Curve Number of tests: □ □ 800V Bias in Wait Period
Inspector: acrobert Module Status: Frontside Encapsulated Configure Test Stand Only IV Test Debug Mode Skip Electrical Checks Close GUI Status Bar- Debug Mode: Is Live Module: Bark Box Closed: DCDC Powered Trophy Connected: CDCP overed Trophy Connected: CDCP overed Trophy Connected: CDCP overed Trophy Connected: CDCP overed CDCP ove	Test Stand IP: cmshgcaltb4.lan.local.cmu.edu	
Module Status: Frontside Encapsulated	Inspector: acrobert	
Configure Test Stand Only IV Test	Module Status: Frontside Encapsulated	Run Tests Restart Services
☑ Debug Mode ☑ Skip Electrical Checks Close GUI Grade Module Status Bar Debug Mode: ● HV Output Powered: ● Trophy Connected: ● Hexacontroller Accessed: ●		End Session
Status Bar Debug Mode: Oracle Module Debug Mode: Dark Box Closed: DCDC Powered Hexacontroller Powered: DAQ Server: Is Live Module: HV Output Powered: Trophy Connected: Hexacontroller Accessed: I2C Server: I2C Server:		
Debug Mode: • Dark Box Closed: • DCDC Powered • Hexacontroller Powered: • DAQ Server: • Is Live Module: • HV Output Powered: • Trophy Connected: • Hexacontroller Accessed: • DAQ Server: •	Debug Mode Skip Electrical Checks Close GUI	
Debug Mode: • Dark Box Closed: • DCDC Powered • Hexacontroller Powered: • DAQ Server: • Is Live Module: • HV Output Powered: • Trophy Connected: • Hexacontroller Accessed: • DAQ Server: •		Grade Module
Debug Mode: • Dark Box Closed: • DCDC Powered • Hexacontroller Powered: • DAQ Server: • Is Live Module: • HV Output Powered: • Trophy Connected: • Hexacontroller Accessed: • DAQ Server: •		
Debug Mode: Oark Box Closed: DCDC Powered Hexacontroller Powered: DAQ Server: DAQ Server: Is Live Module: HV Output Powered: Trophy Connected: Hexacontroller Accessed: DAQ Server: I2C Server:		
Debug Mode: • Dark Box Closed: • DCDC Powered • Hexacontroller Powered: • DAQ Server: • Is Live Module: • HV Output Powered: • Trophy Connected: • Hexacontroller Accessed: • DAQ Server: •	Status Bar	
Is Live Module: HV Output Powered: Trophy Connected: Hexacontroller Accessed: I2C Server:		Hexacontroller Powered: DAO Server:

•A one-stop user interface.

•With one click, it can run all tests and upload the test results to the database.

Ongoing

7 Pre-Production Summary

Time: Apr 2024 -> Aug 2024		4	AA AA A -	_	
	# of Modules		7 0 0 0)	
		< 150 <i>µ</i> m	# of dead < 10) 500 V < Break	
Module IDs	PCB ID	Placement	Electronic	IV	Summary
ML_F3WX_IH_00014	02	Α	Α	Α	AAA
ML_F3WX_IH_00015	09	Α	Α	Α	AAA
ML_F3WX_IH_00016	10	Α	Α	Α	AAA
ML_F3WX_IH_00017	03	Α	Α	Α	AAA
ML_F3WX_IH_00018	01	Α	Α	Α	AAA
ML_F3WX_IH_00019	04	Α	Α	Α	AAA
ML_F3WX_IH_00020	101	Α	Α	Α	AAA
# of A		7	7	7	

- The quality of this batch of PCB boards and sensors is very high.
- This is a unique batch of modules that CERN specifically requested IHEP to assemble, intended exclusively for preliminary beam testing.

10 Pre-Series Summary

Time:			A	AA AA	Α -			
Aug 2024 -	> Nov 2024	# of M	Iodules d	53	0	1		
_				# C.I.		•		
			< 150 µ m	# of dea		0	500 V < Break	
	Module IDs	PCB ID	Placement	Electr	onic		IV	Summary
ML_F	-3WX_IH_00021	84	Α	А	•		Α	AAA
ML_F	-3WX_IH_00022	60	Α	А	•		Α	AAA
ML_F	-3WX_IH_00023	53	Α		-		Α	AA
ML_F	-3WX_IH_00024	45	Α	А	L .		—	AA
ML_F	-3WX_IH_00025	54	(Misaligned)	А	L .		—	—
ML_F	-3WX_IH_00026	55	Α	Α	•		Α	AAA
ML_F	-3WX_IH_00027	56	Α	А	•		Α	AAA
ML_F	-3WX_IH_00028	57	Α	А	•		Α	AAA
ML_F	-3WX_IH_00029	58	Α	_	_		Α	AA
ML_F	-3WX_IH_00030	59	Α	Α	N		Α	AAA
	# of A		9	8	}		8	

• This unique batch of pre-series modules was assembled as a practice run for the upcoming official production. Due to its purpose, the quality of these modules is expectedly lower, allowing us to refine our processes.

• We've already upgraded our system to handle two modules at once, and we've further enhanced our software to prevent human error during assembly.

Summary and Outlook

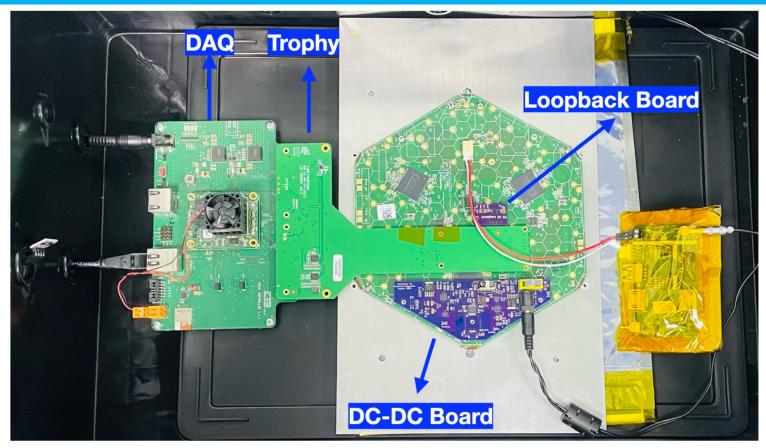
- As of now, IHEP has assembled 40 modules, of which 31 (or 77%) are graded A. The best from the same level of MACs.
- The quality assurance and control (QA/QC) standards are followed.
- QA/QC Standards
 - Alignment
 - Number of Electronic Readout and Noise Level
 - IV Response (Current v.s. Voltage)
- One of crucial procedures in HGCAL assembly.
 - Identified the final quality of HGCAL modules.
 - Make sure no damage caused after each assembly process, including initial quality, taping, gantry assembly, bonding, and encapsulation (Final).
- IHEP was the first institute that identified electrostatic discharge when apply double sides tape onto hexaboard. The corresponding protections were applied.
- GUI, one-stop, multiple test user interface is ongoing.



Backup

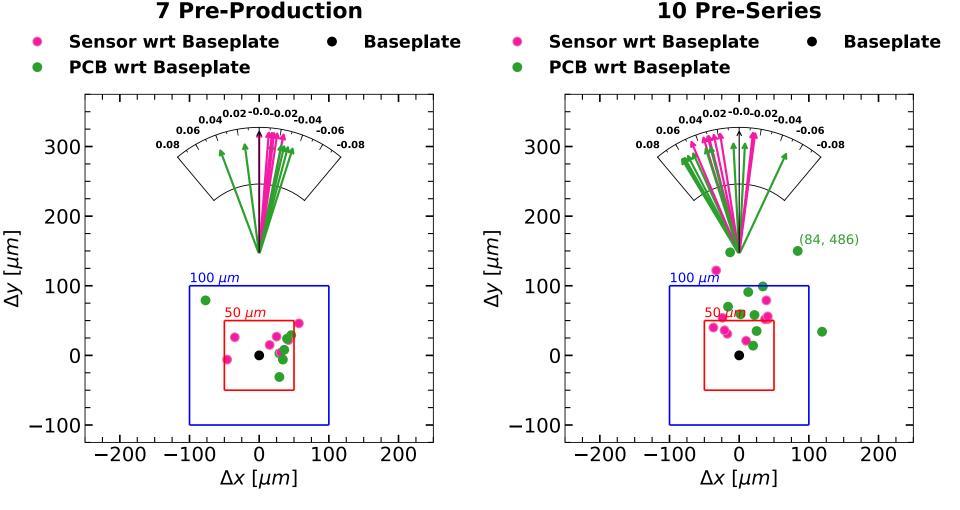
- ➤ Name and Function inside Box
- Placement Accuracy Plots for 7 Pre-Production Modules
- Placement Accuracy Plots for 10 Pre-Series Modules
- ESD Verification by CERN
- ➢ IV curve as Humidity

Name and Function inside Box

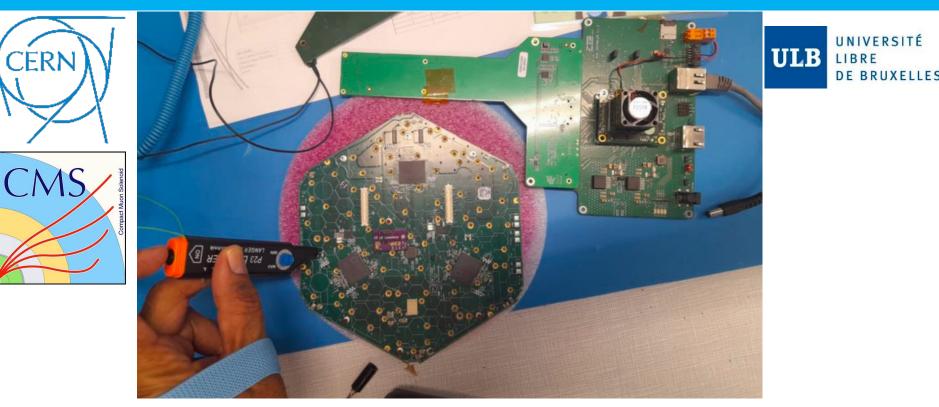


- DAQ: where the microcomputer is and it convert analog to digital
- Trophy: a connector
- DC-DC board: supply low voltage
- Loopback board: distributed the low voltage to other part of module.
- Red-white wire: for measuring IV respond.

Summarized Accuracy Plot



ESD Verification by CERN



Injected ESD pulses across the CM capacitor on pad towards chips.

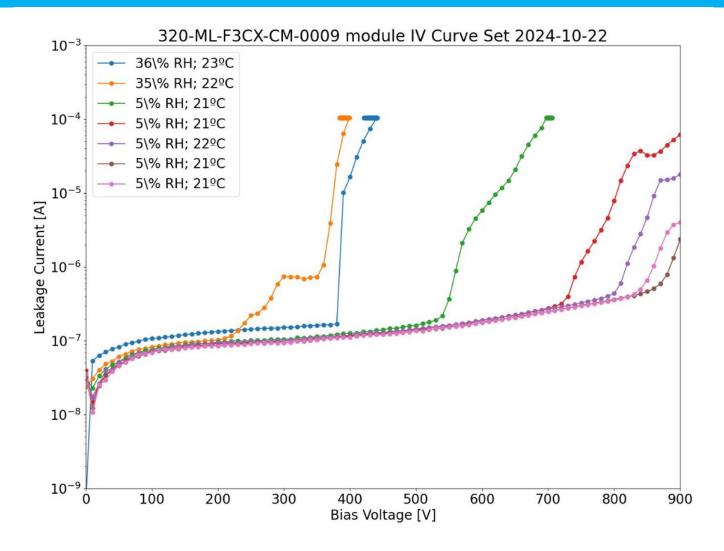
Key conclusions:

- Any analog pin, normal or CM, can be destroyed by an ESD pulse above 600 V if injected at the pins.
- Not only the CM pins but also HV Decoupling Cap can be damaged by ESD.

Advice:

Basic ESD handling precautions must always be followed at every stage, from chip testing to module assembly and beyond.

IV Test as Humidity



• Humidity can have a noticeable impact on IV curve